

BS IEC 60747-14-3: 2009



BSI Standards Publication

Semiconductor devices —

Part 14-3: Semiconductor sensors – Pressure sensors

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National foreword

This British Standard is the UK implementation of IEC 60747-14-3:2009. It supersedes BS IEC 60747-14-3:2001 which is withdrawn.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

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ISBN 978 0 580 62901 3

ICS 31.080.99

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This British Standard was published under the authority of the Standards Policy and Strategy Committee on 31 July 2009

Amendments issued since publication

Amd. No.	Date	Text affected
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INTERNATIONAL STANDARD

NORME INTERNATIONALE

Semiconductor devices ±
Part 14-3: Semiconductor sensors ± Pressure sensors

Dispositifs à semiconducteurs –
Partie 14-3: Capteurs à semiconduc teurs ± Capteurs de pression

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

COMMISSION
ELECTROTECHNIQUE
INTERNATIONALE

PRICE CODE
CODE PRIX

R

ICS 31.080.99

ISBN 2-8318-1039-7

CONTENTS

FOREWORD.....	4
INTRODUCTION.....	6
1 Scope.....	7
2 Normative references	7
3 Terminology and letter symbols	7
3.1 General terms	7
3.1.1 Semiconductor pressure sensors.....	7
3.1.2 Sensing methods.....	7
3.2 Definitions	9
3.3 Letter symbols.....	12
3.3.1 General	12
3.3.2 List of letter symbols	12
4 Essential ratings and characteristics.....	13
4.1 General.....	13
4.1.1 Sensor materials – for piezoelectrical sensors	13
4.1.2 Handling precautions.....	13
4.1.3 Types	13
4.2 Ratings (limiting values)	13
4.2.1 Pressures	13
4.2.2 Temperatures	13
4.2.3 Voltage.....	13
4.3 Characteristics	13
4.3.1 Full-scale span (V_{FSS})	13
4.3.2 Full-scale output (V_{FSO}).....	13
4.3.3 Sensitivity (S).....	13
4.3.4 Temperature coefficient of full-scale sensitivity (α_S)	14
4.3.5 Offset voltage (V_{OS}).....	14
4.3.6 Temperature coefficient of offset voltage (α_{VOS})	14
4.3.7 Pressure hysteresis of output voltage (H_{Ohp})	14
4.3.8 Temperature hysteresis of output voltage (H_{OhT})	14
4.3.9 Response time	14
4.3.10 Warm-up	14
4.3.11 Dimensions	14
4.3.12 Mechanical characteristics.....	14
5 Measuring methods	14
5.1 General.....	14
5.1.1 General precautions	14
5.1.2 Measuring conditions.....	14
5.2 Output voltage measurements	15
5.2.1 Purpose.....	15
5.2.2 Principles of measurement	15
5.3 Sensitivity (S)	16
5.3.1 Purpose.....	16
5.3.2 Measuring procedure.....	16
5.3.3 Specified conditions	16
5.4 Temperature coefficient of sensitivity (α_S)	16

5.4.1	Purpose.....	16
5.4.2	Specified conditions	16
5.5	Temperature coefficient of full-scale span (αV_{FSS}) and maximum temperature deviation of full-scale span (ΔV_{FSS})	17
5.5.1	Purpose.....	17
5.5.2	Specified conditions	17
5.6	Temperature coefficient of offset voltage (αV_{OS}) and (ΔV_{OS}).....	17
5.6.1	Purpose.....	17
5.6.2	Specified conditions	17
5.7	Pressure hysteresis of output voltage (H_{Ohp})	18
5.7.1	Purpose.....	18
5.7.2	Circuit diagram and circuit description	18
5.7.3	Specified conditions	18
5.8	Temperature hysteresis of output voltage (H_{OhT})	18
5.8.1	Purpose.....	18
5.8.2	Measuring procedure.....	18
5.8.3	Specified conditions	18
5.9	Linearity	18
5.9.1	Purpose.....	18
5.9.2	Specified conditions	18
5.9.3	Measuring procedure.....	18
Figure 1 – Basic circuit for measurement of output voltage		15
Figure 2 – Linearity test		19

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SEMICONDUCTOR DEVICES ±**Part 14-3: Semiconductor sensors ±
Pressure sensors**

FOREWORD

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International Standard IEC 60747-14-3 has been prepared by subcommittee 47E: Discrete semiconductor devices, of IEC technical committee 47: Semiconductor devices.

This second edition cancels and replaces the first edition, published in 2001, and constitutes a technical revision.

The major technical changes with regard to the previous edition are as follows: added a new Subclause 5.9 (measuring method of linearity) (technical)

The text of this standard is based on the following documents:

CDV	Report on voting
47E/362/CDV	47E/376/RVC

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

This part of IEC 60747 should be read in conjunction with IEC 60747-1:2006.

A list of all the parts in the IEC 60747 series, under the general title *Semiconductor devices*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

INTRODUCTION

This part of IEC 60747 provides basic information on semiconductors:

- terminology;
- letter symbols;
- essential ratings and characteristics;
- measuring methods;
- acceptance and reliability.